

IN THE CLAIMS:

1. (currently amended) A method for inspecting a component, said method comprising:

coupling the component to a fixture such that the component is fixedly secured in position during machining of the component; and

inspecting the component using an inspection tool while the component is coupled to the fixture, wherein the inspection tool includes a probe having at least a first and a second probe tip that are each selectively positionable with respect to each other.

2. (original) A method in accordance with Claim 1 wherein coupling the component to a fixture further comprises machining the component using a machining apparatus while the component is coupled to the fixture.

3. (original) A method in accordance with Claim 2 wherein inspecting the component further comprises coupling the inspection tool to at least one of the fixture and the machining apparatus.

4. (original) A method in accordance with Claim 1 wherein inspecting the component further comprises measuring at least one of a thickness and a length of the component.

5. (currently amended) A method in accordance with Claim 1 wherein ~~the inspection tool includes a probe having at least a first and a second probe tip,~~ inspecting the component further comprises measuring a thickness of the component using the first and the second probe tips.

6. (original) A method in accordance with Claim 5 wherein measuring a thickness of the component comprises:

positioning the first probe tip in contact with a first surface of the component;

positioning the second probe tip in contact with a second surface of the component;

and

determining a thickness of the component using the location of the first probe tip and the location of the second probe tip.

7-20. (canceled)